

Notice of References Cited	Application/Control No. 10/523,468		Applicant(s)/Patent Under Reexamination OESTERSCHULZE ET AL.	
	Examiner William P. Watkins III		Art Unit 1794	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-			
	B	US-			
	C	US-			
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FOREIGN PATENT DOCUMENTS

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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Olschimg, J., et al., "Fabrication of 15 um thick SI-Hole Masks for Demagnifying Projection Systems For Ion or Electron Beams", Microelectronic Engineering, (1987) North Holland, Vol. 6, pages 547-552.
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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